

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1724		SERIAL NO. 09/905,286	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Cem Basceri et al.		FILING DATE July 13, 2001	
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
EF	AA	4,261,698	04/81	Carr et al.			
	AB	4,691,662	09/87	Roppel et al.			
	AC	5,261,961	11/93	Takasu et al.			
	AD	5,270,241	12/93	Dennison et al.			
	AE	5,312,783	05/94	Takasaki et al.			
	AF	5,392,189	02/95	Fazan et al.			
	AG	5,395,771	03/95	Nakato			
	AH	5,468,687	11/95	Carl et al.			
	AI	5,525,156	06/96	Manada et al.			
	AJ	5,614,018	03/97	Azuma et al.			
	AK	5,656,329	08/97	Hampden-Smith			
	AL	5,663,089	09/97	Tomozawa et al.			

FOREIGN PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
EF	AM	EP 0 030 798	06/81	EPO			
	AN	GB 2 194 555 A	03/88	United Kingdom			
	AO	EP 0 306 069 A2	03/89	EPO			
	AP	EP 0 388 957 A2	09/90	EPO			
	AQ	JP2250970	10/90	Japan			

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
EF	AR	Aoyama et al., <i>Leakage Current Mechanism of Amorphous and Polycrystalline Ta<sub>2</sub>O<sub>5</sub> Films Grown by Chemical Vapor Deposition</i> , 143 J. ELECTROCHEM SOC., No. 3, pp 977-983 (March 1996).
		Stemmer et al., <i>Accommodation of nonstoichiometry in (100) fiber-textured (Ba<sub>x</sub>Sr<sub>1-x</sub>)Ti<sub>1-y</sub>O<sub>3-z</sub> thin films grown by chemical vapor deposition</i> , 74 APPL. PHYS. LETT., No. 17, pp. 2432-2434 (26 April 1999).
EF	AS	Streiffer et al., <i>Ferroelectricity in thin films: The dielectric response of fiber-textured (Ba<sub>x</sub>Sr<sub>1-x</sub>)Ti<sub>1-y</sub>O<sub>3-z</sub> thin films grown by chemical vapor deposition</i> , 86 J. APPL. PHYS. No. 8, pp. 4565-4575 (15 October 1999).

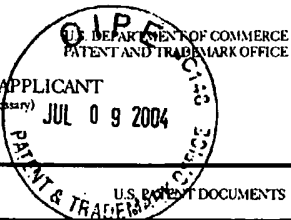
  

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## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
EF	AA	5,702,562	12/97	Wakahara			
	AB	5,719,417	02/98	Roeder et al.			
	AC	5,723,361	03/98	Azuma et al.			
	AD	5,736,759	04/98	Hausaalter			
	AE	5,976,990	11/99	Mercaldi et al.			
	AF	5,989,927	11/99	Yamonobe			
	AG	6,101,085	08/00	Kawahara et al.			
	AH	6,215,650	04/01	Gnade et al.			
	AI	6,258,654	07/01	Gocho			
	AJ	6,287,935 B1	09/01	Coursey			
	AK	6,325,017 B1	12/01	DeBoer et al.			
EF	AL	6,335,049 B1	01/02	Basceri			

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
EF	AM	04-24922	01/92	Japan				
	AN	04-115533	04/92	Japan				
	AO	04-180566	06/92	Japan				
	AP	08-060347	03/96	Japan				
EF	AQ	EP 0 810 666 A1	12/97	EPO				

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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U.S. PATENT DOCUMENTS  
PATENT & TRADEMARK OFFICE

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
EF	AA	6,566,147 B2	05/03	Basceri et al.			
	AB						
	AC						
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	AE						
	AF						
	AG						
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	AI						
	AJ						
	AK						
	AL						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
EF	AM	EP 0 892 426 A2	01/99	EPO				
EF	AN	JP2000091333	03/00	Japan				
EF	AO	WO 01/16395	03/01	WIPO				
	AP							
	AQ							

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Form PTO-1449 <div style="border: 1px solid black; border-radius: 50%; padding: 10px; display: inline-block; text-align: center;"> <b>PTO</b>  <b>JUN 11 2003</b>  <b>RECEIVED</b>  <b>TC 1700</b> </div>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1724		SERIAL NO. 09/003,286	
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U.S. PATENT DOCUMENTS				GROUP 1761			
Examiner	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
EF	AA	6,337,496 B2	01-2002	Jung			
EF	AB	6,507,060 B2	01-2003	Ren et al.			
	AC						
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